

<b>Notice of References Cited</b>	Application/Control No. 10/805,890		Applicant(s)/Patent Under Reexamination NALLAN ET AL.	
	Examiner Binh X. Tran		Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,492,222	12-2002	Xing, Guoqiang	438/240
*	C	US-2002/0142609	10-2002	Hart et al.	438/710
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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